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**INFORMATION DISCLOSURE STATEMENT
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Applicant: MATSUDA et al.

Appln. No.: UNASSIGNED

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of

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Examiner: D. LE

Group Art Unit: 2818

U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
CLP	AR	6,319,807	11/2001	Yeh et al.			
CLP	BR	6,353,249	03/2002	Boyd et al.			
CLP	CR	5,856,225	01/1999	Lee et al.			
CLP	DR	6,087,208	07/2000	Krivokapic et al.			
	ER						
	FR						
	GR						
	HR						
	IR						
	JR						
	KR						
	LR						
	MR						
	NR						

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name		Abstract		Readily Available	
							Enclosed	No	Enclose	No
	OR									
	PR									
	QR									
	RR									
	SR									
	TR									
	UR									

OTHER (including in this order: Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

CLP	VR	A. Chatterjee et al., "Sub-100nm Gate Length Metal Gate NMOS Transistors Fabricated by a Replacement Gate Process," IEDM, 1997, pp. 821-824								
CLP	WR	A. Chatterjee et al., "CMOS Metal Replacement Gate Transistors Using Tantalum Pentoxide Gate Insulator," IEDM, 1998, pp. 777-780								
CLP	XR	Yagishita et al., "High Performance Metal Gate MOSFETs Fabricated by CMP for 0.1um Regime," IEDM 1998, pp. 785-788								
	YR									
	ZR									
	AAR									

Examiner *Shuman N. Nagee*

Date Considered: 12/08/04

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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